

## ABSTRACT OF THE DISCLOSURE

A method and apparatus for modifying a frequency of an oscillating signal comprises generating an oscillating signal of a predetermined frequency on a semiconductor device used as an evaluation test chip by connecting a predetermine number of circuit elements in a ring oscillator configuration. A delay element operably coupled into the ring oscillator configuration modifies the predetermined frequency of the ring oscillator configuration. The operable coupling may occur on a semiconductor package containing the semiconductor device or a circuit board containing the semiconductor device. A ring oscillator is also described.

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